

<b>Notice of References Cited</b>	Application/Control No. 10/667,140		Applicant(s)/Patent Under Reexamination BICSAK ET AL.	
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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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*	B	US-6,907,598	06-2005	Fraser, Christopher Warwick	717/140
*	C	US-4,953,084	08-1990	Meloy et al.	717/131
*	D	US-5,790,867	08-1998	Schmidt et al.	717/155
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	L	US-			
	M	US-			

#### FOREIGN PATENT DOCUMENTS

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#### NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)				
	U	Sutter et al., "Sifting out the Mud: Low Level C++ Code Reuse" OOPSLA'02, ACM, November 2002, pp. 275-291.				
	V	Cooper et al, "Enhanced Code Compression for Embedded RISC Processors", SIGPLAN'99, ACM, 1999, pp. 139-149.				
	W	Baker, Brenda S. "A Theory of Parameterized Pattern Matching: Algorithms and Applications (Extended Abstract)" 25 <sup>th</sup> ACM STOC, 1993, pp. 71-80.				
	X	Debray et al., "Combining Global Code and Data Compaction", LCTES, ACM 2001, pp. 29-38.				

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

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	U	Beszedes et al., "Survey of Code-Size Reduction Methods", ACM Computing Surveys, Vol. 35, No. 3, September 2003, pp. 223-267.
	V	Chanet et al., "Post-Pass Compaction Techniques", Communications of the ACM, Volume 46, Number 8, August 2003, pp. 41-46.
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